

Pat nt Abstracts of Japan

PUBLICATION NUMBER : 11233634
PUBLICATION DATE : 27-08-99

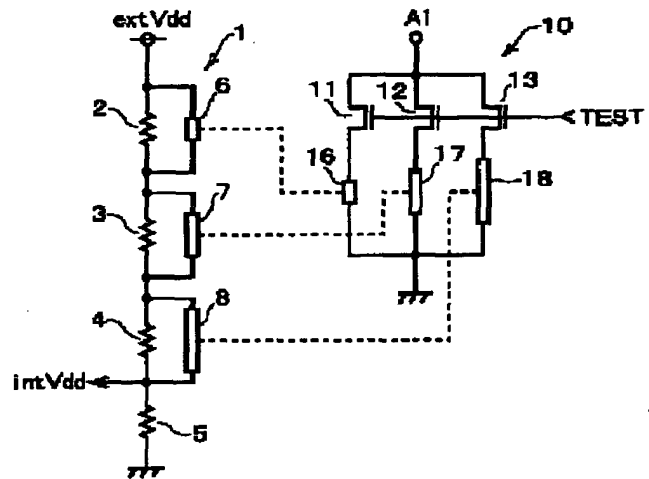
APPLICATION DATE : 12-02-98
APPLICATION NUMBER : 10029474

APPLICANT : MITSUBISHI ELECTRIC ENGINEERING
CO LTD;

INVENTOR : SAKAMI KAZUHIRO;

INT.CL. : H01L 21/82

TITLE : SEMICONDUCTOR INTEGRATED
CIRCUIT



ABSTRACT : **PROBLEM TO BE SOLVED:** To provide a semiconductor integrated circuit which is capable of easily and accurately reading information on the voltage adjustment value of an internal source voltage, etc., in a wafer state, and read the recorded information out after dicing and molding.

SOLUTION: A fuse circuit 10 consisting of fuses 16 to 18 having different resistance values are formed in respective peripheral spaces of respective chips. In the wafer state, the fuses 6 to 8 of a tuning circuit 1 are selected and blown, and the fuses 16 to 18 of the corresponding the fuse circuit 10 for storage are blown and disconnected. When a specific signal TEST is inputted to the fuse circuit 10 for storage after dicing and molding, the composite resistance of undisconnected fuses of the fuse circuit 10 for storage can be measured. The blown fuses of the fuse circuit for storage can be known from the measured resistance value.

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